

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

219507US2S DIV

SERIAL NO.

New Divisional Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hideo ANDO, et al.

FILING DATE

Herewith

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HW</i>	AA	5,687,160	11/97	Aotake et al.	11	11	
<i>HW</i>	AB	5,731,852	03/98	Lee	11	11	
<i>HW</i>	AC	6,185,365	02/01	Murase et al.	11	11	
<i>HW</i>	AD	6,067,400	05/00	Saeki et al.	11	11	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

11002 U.S. PTO
10/076284
02/19/02

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	7-143429	06-02-95	JAPAN		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

HWY NGUYEN

Date Considered

11/1/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 219507US-2S DIV		SERIAL NO. 10/076,284	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO et al.			
				FILING DATE February 19, 2002		GROUP 2615	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HN</i>	AA	5,712,947	1-27-1998	Oguro et al.	<u> </u>	<u> </u>	
<i>HN</i>	AB	6,148,138	11-14-2000	Sawabe et al.	<u> </u>	<u> </u>	
	AC						
	AD						
	AE						
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	AH						
	AI						
	AJ						
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	AL						
	AM						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>HN</i>	AO	JP 5-158778	6-25-1993	Japan	X		
<i>HN</i>	AP	JP 5-165935	7-2-1993	Japan			X
<i>HN</i>	AQ	JP 8-205014	8-9-1996	Japan	X		
<i>HN</i>	AR	JP 9-182013	7-11-1997	Japan	X		
<i>HN</i>	AS	JP 11-136613	5-21-1999	Japan	X		
	AT						
	AU						
	AV						
	AW						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>HN</i>	AW	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 2002-87033 (with English Translation).					
<i>HN</i>	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 1998-192063 (with English Translation).					
<i>HN</i>	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. 1999-256210 (with English Translation).					
	AZ						
Examiner <i>HOY NGUYEN</i>					Date Considered <i>1/11/03</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							